Welcome to Galaxy Examinator reports

Date: Tue Sep 3 11:37:54 2024
Product :
LotID :

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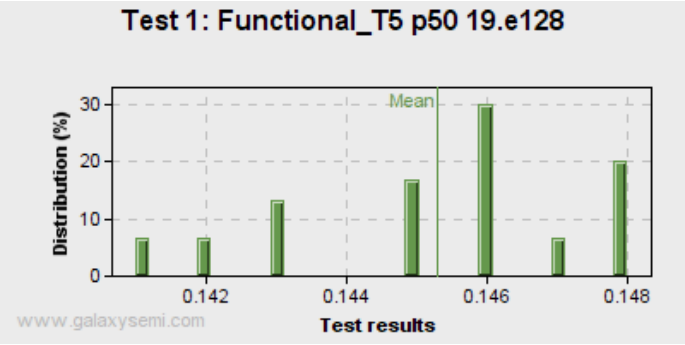
Tests Statistics

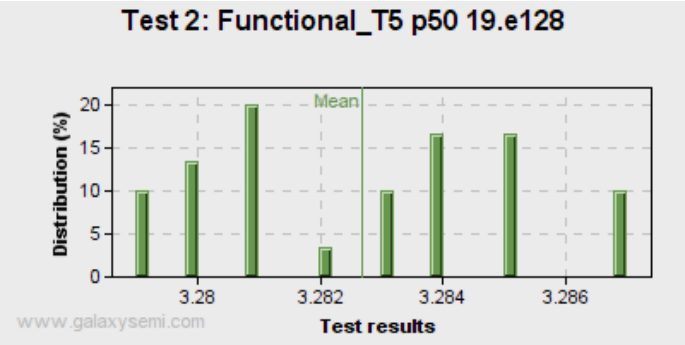
Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
1	Functional_T5 p50 19.e128	P	n/a .	n/a .	Samples	30	0	0.1453	0.00215198	n/a .	n/a .	100.00 %
2	Functional_T5 p50 19.e128	P	n/a .	n/a .	Samples	30	0	3.28267	0.00248213	n/a .	n/a .	100.00 %
4	Functional_T6 p50 19.e128	P	150 ns	350 ns	Samples	30	0	233.333 ns	1.91785 ns	17.38	14.48	100.00 %
5	Functional_T6 p50 19.e128	P	150 ns	350 ns	Samples	30	0	244.8 ns	1.34933 ns	24.70	23.42	100.00 %
6	Functional_T6 A8 0	P	1 ns	100 ns	Samples	30	0	11.4667 ns	2.22421 ns	7.42	1.57	100.00 %
7	Functional_T7 p53 19.e135	P	n/a .	n/a .	Samples	30	0	3.28323 V	0.00173571 V	n/a .	n/a .	100.00 %
8	Functional_T7 p53 19.e135	P	n/a .	n/a .	Samples	30	0	0.138933	0.00222731	n/a .	n/a .	100.00 %
12	Functional_T8 A8 0	P	1 ns	20 ns	Samples	30	9	302.933 ns	911.086 ns	0.0035	−0.1035	70.00 %
786000	Soft_Bin parameter	–	n/a .	n/a .	Samples	30	0	1	0	n/a .	n/a .	100.00 %
786001	Hard_Bin parameter	–	n/a .	n/a .	Samples	30	0	1	0	n/a .	n/a .	100.00 %
786002	Die_X parameter	–	n/a .	n/a .	Samples	30	0	2	1.43839	n/a .	n/a .	100.00 %
786003	Die_Y parameter	–	n/a .	n/a .	Samples	30	0	2.5	1.73702	n/a .	n/a .	100.00 %
786004	Test_Time parameter	–	0.0 sec	n/a .	Samples	30	0	2.03003 sec	0.0797057 sec	n/a .	8.49	100.00 %
786006	Testing_Site parameter	–	n/a .	n/a .	Samples	30	0	0	0	n/a .	n/a .	100.00 %
786007	Part_ID parameter	–	n/a .	n/a .	Samples	30	0	15.5	8.80341	n/a .	n/a .	100.00 %

Histogram of Tests

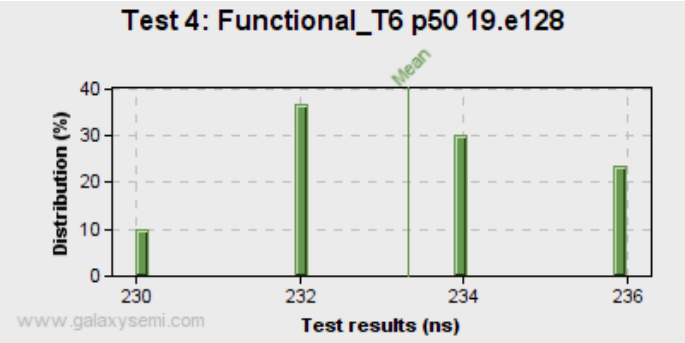
Test	1
Name	Functional_T5 p50 19.e128
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	0.1453
Sigma	0.00215198
Range	0.007
Cp / Cpk	n/a . / n/a .
Samples	30



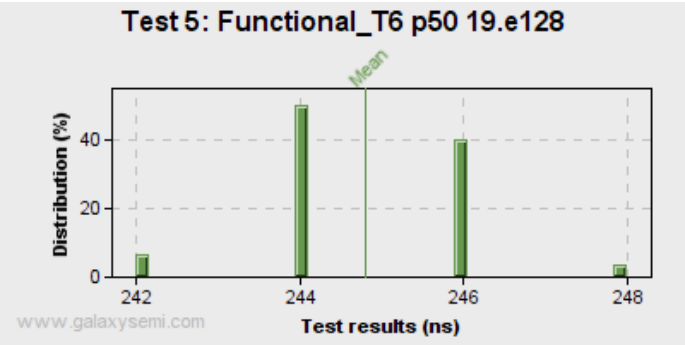
Test	2
Name	Functional_T5 p50 19.e128
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	3.28267
Sigma	0.00248213
Range	0.0079999
Cp / Cpk	n/a . / n/a .
Samples	30



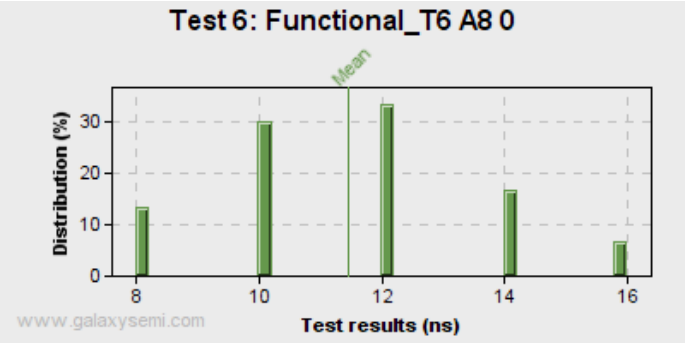
Test	4
Name	Functional_T6 p50 19.e128
Test type	Parametric
Low limit	150 ns
High limit	350 ns
Exec / Fails	30 / 0 (0.00%)
Mean	233.333 ns
Sigma	1.91785 ns
Range	6.00001 ns
Cp / Cpk	17.38 / 14.48
Samples	30



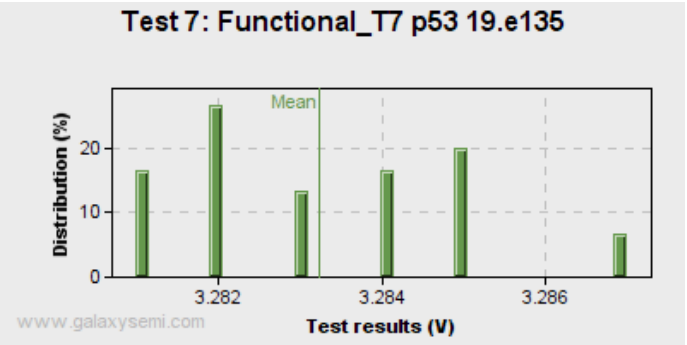
Test	5
Name	Functional_T6 p50 19.e128
Test type	Parametric
Low limit	150 ns
High limit	350 ns
Exec / Fails	30 / 0 (0.00%)
Mean	244.8 ns
Sigma	1.34933 ns
Range	5.99999 ns
Cp / Cpk	24.70 / 23.42
Samples	30



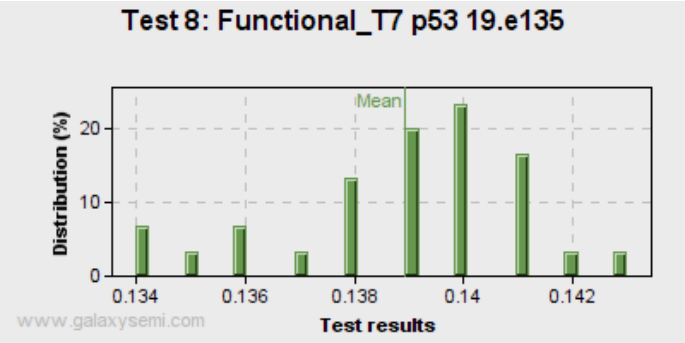
Test	6
Name	Functional_T6 A8 0
Test type	Parametric
Low limit	1 ns
High limit	100 ns
Exec / Fails	30 / 0 (0.00%)
Mean	11.4667 ns
Sigma	2.22421 ns
Range	8 ns
Cp / Cpk	7.42 / 1.57
Samples	30



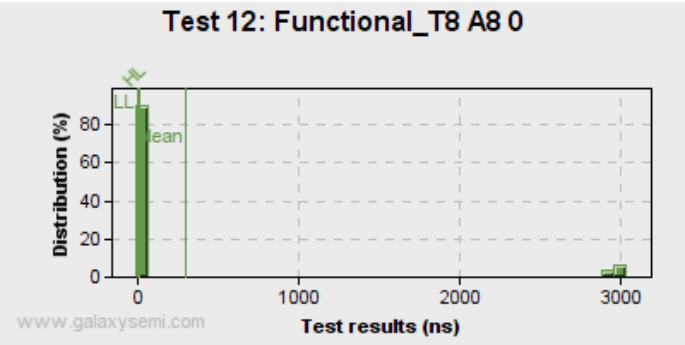
Test	7
Name	Functional_T7 p53 19.e135
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	3.28323 V
Sigma	0.00173571 V
Range	0.00600004 V
Cp / Cpk	n/a . / n/a .
Samples	30



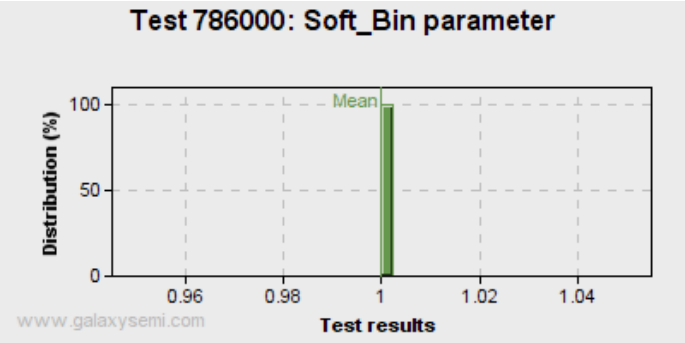
Test	8
Name	Functional_T7 p53 19.e135
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	0.138933
Sigma	0.00222731
Range	0.009
Cp / Cpk	n/a . / n/a .
Samples	30



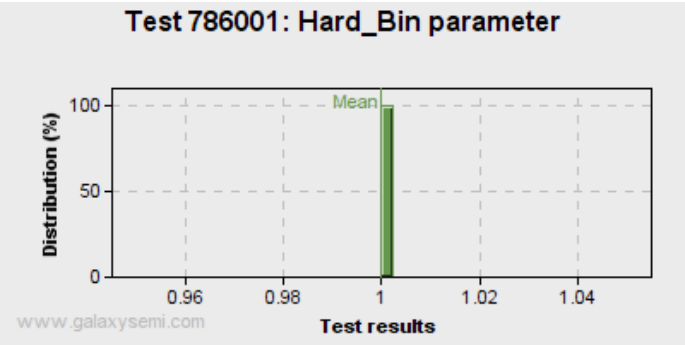
Test	12
Name	Functional_T8 A8 0
Test type	Parametric
Low limit	1 ns
High limit	20 ns
Exec / Fails	30 / 9 (30.00%)
Mean	**302.933 ns**
Sigma	911.086 ns
Range	3044 ns
Cp / Cpk	0.0035 / −0.1035 ....=&gt Warning: Process is over the high limit
Samples	30



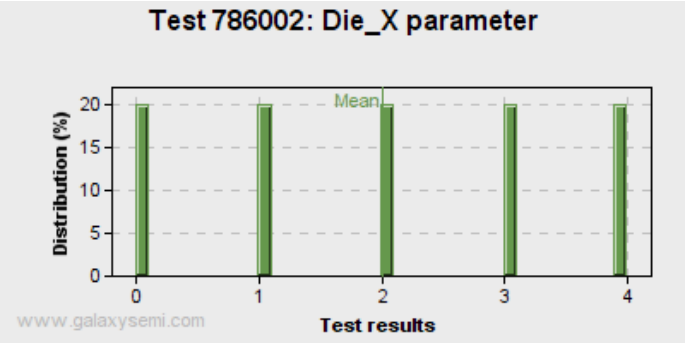
Test	786000
Name	Soft_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	30



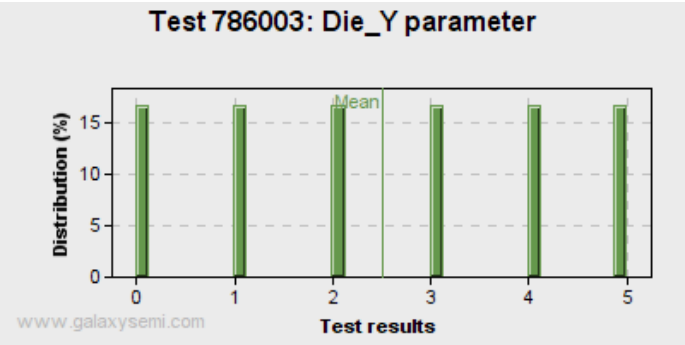
Test	786001
Name	Hard_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	30



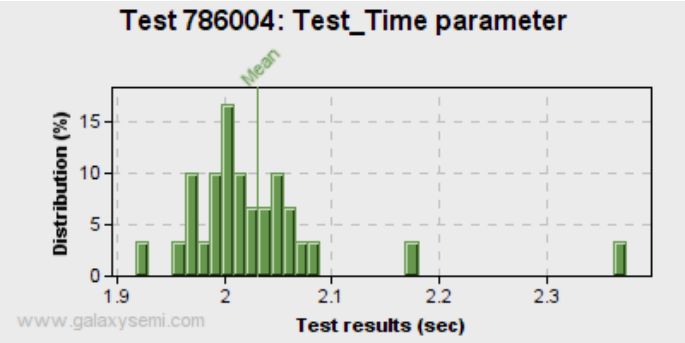
Test	786002
Name	Die_X parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	2
Sigma	1.43839
Range	4
Cp / Cpk	n/a . / n/a .
Samples	30



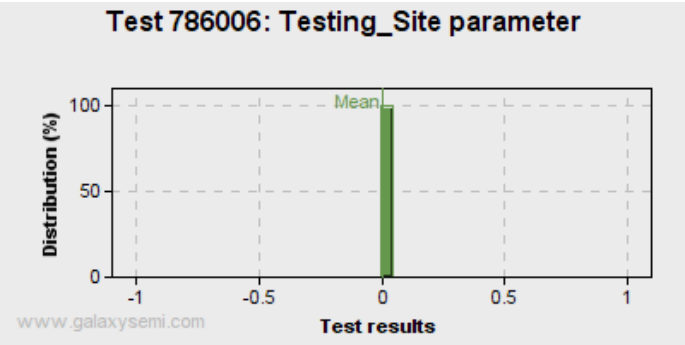
Test	786003
Name	Die_Y parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	2.5
Sigma	1.73702
Range	5
Cp / Cpk	n/a . / n/a .
Samples	30



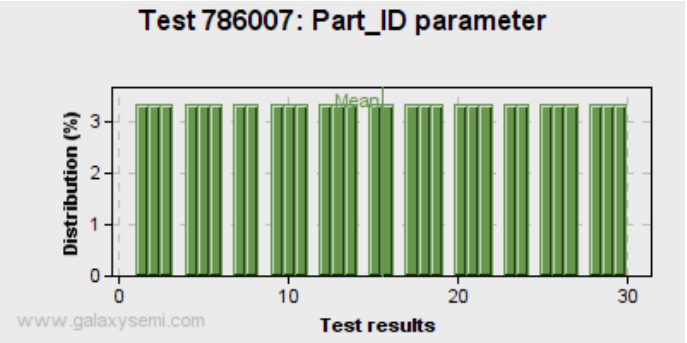
Test	786004
Name	Test_Time parameter
Test type	–
Low limit	0.0 sec
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	2.03003 sec
Sigma	0.0797057 sec
Range	0.457 sec
Cp / Cpk	n/a . / 8.49
Samples	30



Test	786006
Name	Testing_Site parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	0
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	30



Test	786007
Name	Part_ID parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	15.5
Sigma	8.80341
Range	29
Cp / Cpk	n/a . / n/a .
Samples	30



Pareto of Tests Cp

Test	Name	Cp	Test Cp Chart
12	Functional_T8 A8 0	0.0035	

Shows all Cp <= 1.7 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests Cpk

Test	Name	Cpk	Test Cpk Chart
12	Functional_T8 A8 0	−0.1035	

Shows all Cpk <= 1.3 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests failures

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
12	Functional_T8 A8 0	–	9	30.0 %	n/a	30.0 %	
–	**Cumul. of failures**	–	**9**	**30.0 %**	**0.0 %**	**30.0 %**	

-– Yield loss: number of failed test executions / number of parts
-– Fail contribution: number of failed test executions / number of parts failed
-– Test Fail rate: number of failed test executions / number of test executions

Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **30**
Total patterns detected: **1**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)
9	100.00 %	30.00 %	Functional_T8 A8 0 (Test 12)
9	**100 %**	**–**	**Total failures detected**

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut−off limit')

Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected

Pareto of Software Bins

Software Binning	Bin Name	Count	Percentage	Software Binning Chart
1	–	30	100.0 %	
Cumul.	Cumul.	30	100.0%	

Pareto of Hardware Bins

Hardware Binning	Bin Name	Count	Percentage	Hardware Binning Chart
1	–	30	100.0 %	
Cumul.	Cumul.	30	100.0%	

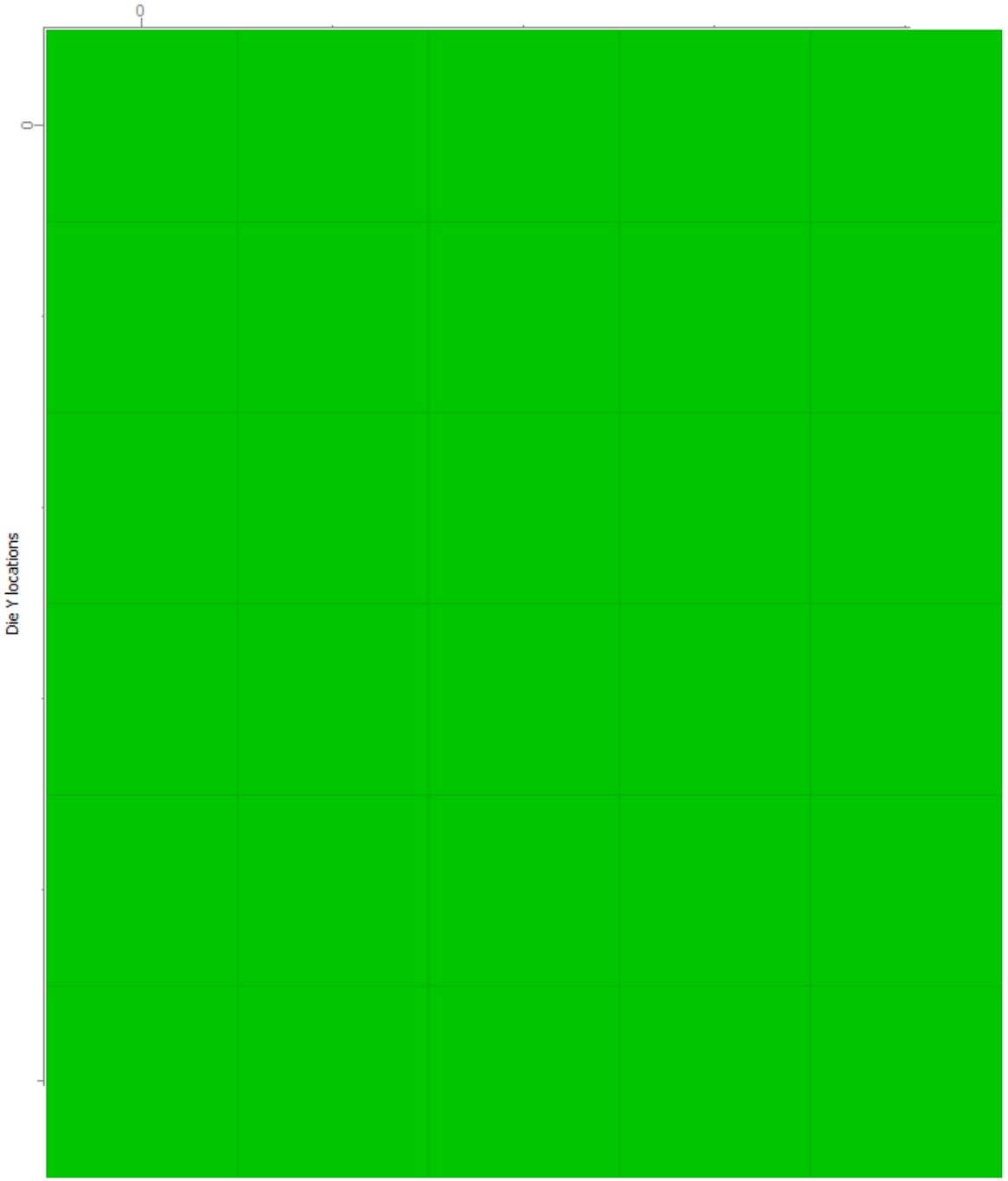
Wafermaps & Strip Maps

Map type	Show Software bins
Devices tested (with retests)	30
Total physical parts tested	30 (only applies to Wafermaps)

List of Individual Maps

Top 10 Software Binning	1
Color	
Pass/Fail	P
Percentage	100.0%
Total count	30

Map style	STRIP map (parts tested are PACKAGED DEVICES!)
Total physical parts tested	30
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Strip started	Tue Sep 03 23:24:56 2024
Strip ended	Tue Sep 03 23:33:32 2024
Wafer tested in	8 minutes 36 seconds
Average device test time	17.200 sec.
Map dimensions	LowX=0, LowY=0, HighX=4, HighY=5


0
0
Die Y locations

Run 1, Run 2,...

Software Binning Summary

Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	–	P	30	100.0 %	
All PASS Bins	**All PASS Bins**	P	**30**	**100.0 %**	
ALL Bins	**ALL Bins**	–	**30**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Hardware Binning Summary

Hardware Binning	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	–	P	30	100.0 %	
All PASS Bins	All PASS Bins	P	30	100.0 %	
ALL Bins	ALL Bins	–	30	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Message Log

No log message to report

Global Information

Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Tue Sep 03 11:37:54 2024
Data processed	44.6 KB (45653 bytes)
Processing time	0.37 second
Processing speed	120.8 KB/sec
Examinator expires	Sun Sep 3 2034
(null)	–
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/rahmana_i8243_p1.igxl_09032024_233054.std
Tests mapping file	n/a

Setup time	Tue Sep 03 23:24:56 2024
Start time	Tue Sep 03 23:24:56 2024
End time	Tue Sep 03 23:33:32 2024
Test duration	8 minutes 36 seconds
Product	n/a
Program	rahmana_i8243_p1.igxl
Revision	n/a
Lot	n/a
Sub−Lot	n/a
WaferID	n/a
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Test time (GOOD parts)	2.030 sec. (excludes tester idle time)
Test time (ALL parts)	2.030 sec. (excludes tester idle time)
Average test time	17.200 sec. / device (includes tester idle time between parts)
Total parts tested	30 − Includes parts retested (if any)
Good parts (Yield)	30 (100.00%) − Includes parts retested (if any)
Bad parts (Yield loss)	0 (0.00%) − Includes parts retested (if any)
Parts retested	n/a .
Parts aborted	0 (0.00%)
(null)	−
STDF Version	4.0
Tester name	SNG−UFP−789
Tester type	UltraFLEXplus
Station	1
Part type	n/a
Operator	rahmana
Exec_type	IG−XL
Exec_version	10.30.10_uflx (P1.11)
TestCode	n/a
Test Temperature	n/a
User Text	n/a
Aux_file	n/a
Package type	n/a
Per_freq	n/a
Spec_name	n/a
Spec_version	n/a
Family ID	n/a

Date code	n/a
Design Rev	n/a
Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	–
Site details	Site# 0

Global Options

Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift